Allied High Tech Products, Inc. 2020 Product/Application Overview



Introduction

- Allied High Tech Products, Inc.
 - 35+ years
 - Specializing in Sample Preparation
- Gary Liechty gdliechty@alliedhightech.com
 - > 25+ years experience in sample prep
 - Author/co-author and contributor to several (IEEE) published works on sample prep
 - Co-inventor/engineer of the MultiPrep (1998)
 - Over 3K units worldwide
 - Co-developer X-Prep (2008)
 - 150+ units worldwide



MultiPrep

- High precision grinding/polishing machine
- Precision mechanical control of sample
 - Tilt/axis control
 - Dynamic and static indication of position/material removal
- Suited mostly for small/unencapsulated samples contemporary applications
 - Flat wheel/platen uses disc form abrasives/cloths for grinding/polishing
- Introduced 1998
 - Optical and Electron Microscopy Sample Prep
 - Semiconductor, Material Research
- Cross-sectioning for SEM/TEM sample prep
 - Package Defect Analysis
 - Solder ball/bond wire and die attach
 - Au (2005) Cu (2004 to present) Ag & SnPb to SnAg (RoHs) artifacts in prep
 - Thin-film (TEM)
- Parallel delayering/deprocessing
 - Die level deprocessing/reverse engineering
 - Challenges with uniformity due to curvature



X-Prep

- Highly specific, precision mechanical (CNC type) milling instrument introduced 2008
 - Small diameter cutting and diamond grinding tools as well as polishing abrasives
 - Non-planar sample prep
- Semiconductor applications (mostly)
- Addresses challenges of semi in shrinking scale/package density and complexity due to drive to newer technologies
 - Curvature, stress/warpage
 - Enables EFI for DPA locate (electrical)the physical defect, verify through crosssection (physical dest.)
- Extends benefits of CNC milling to FA with easier to use interface and level of precision required in semi
- Uses miniature cutting and diamond grinding tools for mechanical removal (cutting/grinding) of materials without damage to the functionality of the sample/device
 - Highly versatile
 - Micron level precision



Thank you for your attention.

X Questions?

